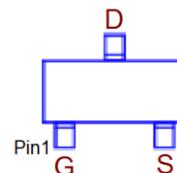
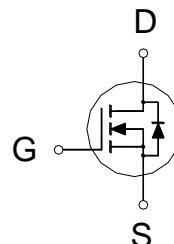


NIKO-SEM**N-Channel Enhancement Mode
Field Effect Transistor****PM514BA
SOT-23(S)
Halogen-Free & Lead-Free****PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
20V	40mΩ	3.3A

G. GATE
D. DRAIN
S. SOURCE**ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS		UNITS
Gate-Source Voltage		V_{GS}	± 8		V
Continuous Drain Current	$T_A = 25^\circ\text{C}$	I_D	3.3		A
	$T_A = 70^\circ\text{C}$		2.7		
Pulsed Drain Current ¹		I_{DM}	12		
Power Dissipation	$T_A = 25^\circ\text{C}$	P_D	0.7		W
	$T_A = 70^\circ\text{C}$		0.4		
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150		°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ²	$R_{\theta JA}$		170	°C/W

¹Pulse width limited by maximum junction temperature.²The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$.**ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	20			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	0.5	0.7	1	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 8\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 16\text{V}, V_{GS} = 0\text{V}$			1	μA
		$V_{DS} = 10\text{V}, V_{GS} = 0\text{V}, T_J = 55^\circ\text{C}$			10	
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = 1.8\text{V}, I_D = 2.5\text{A}$		55	80	$\text{m}\Omega$
		$V_{GS} = 2.5\text{V}, I_D = 2.8\text{A}$		36	50	
		$V_{GS} = 4.5\text{V}, I_D = 3\text{A}$		29	40	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 5\text{V}, I_D = 3\text{A}$		16		S

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DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 10V, f = 1MHz$		331		pF
Output Capacitance	C_{oss}			56		
Reverse Transfer Capacitance	C_{rss}			44		
Total Gate Charge ²	Q_g	$V_{DS} = 10V, V_{GS} = 4.5V, I_D = 3A$		5		nC
Gate-Source Charge ²	Q_{gs}			0.6		
Gate-Drain Charge ²	Q_{gd}			1.7		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DD} = 10V, I_D \approx 3A, V_{GEN} = 4.5V, R_G = 6\Omega$		30		nS
Rise Time ²	t_r			30		
Turn-Off Delay Time ²	$t_{d(off)}$			90		
Fall Time ²	t_f			31		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current	I_S			0.7	A	
Forward Voltage ¹	V_{SD}	$I_F = 3A, V_{GS} = 0V$		1	V	
Reverse Recovery Time	t_{rr}	$I_F = 3A, dI_F/dt = 100A/\mu S$		10		nS
Reverse Recovery Charge	Q_{rr}			2		nC

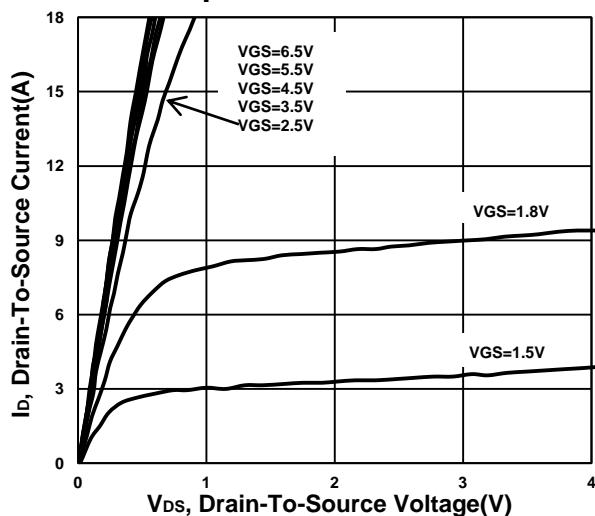
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

NIKO-SEM

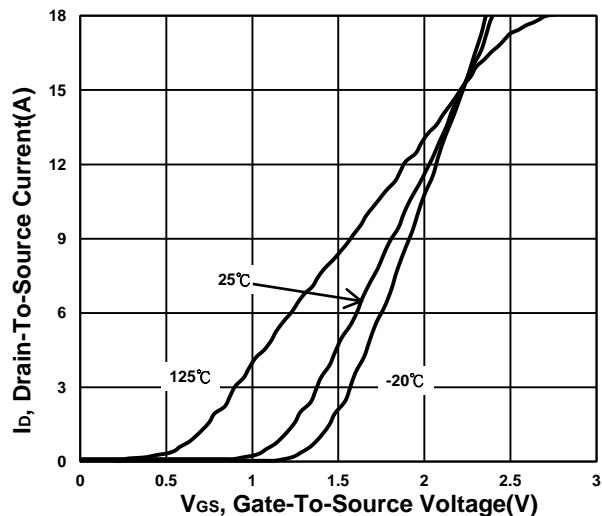
**N-Channel Enhancement Mode
Field Effect Transistor**

PM514BA
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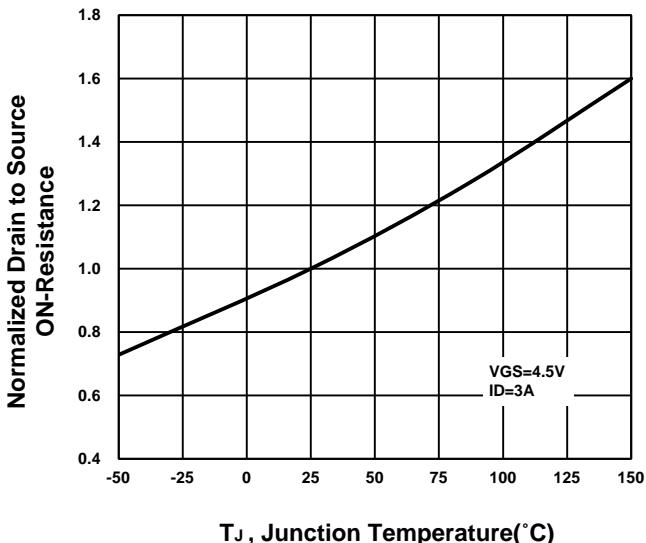
Output Characteristics



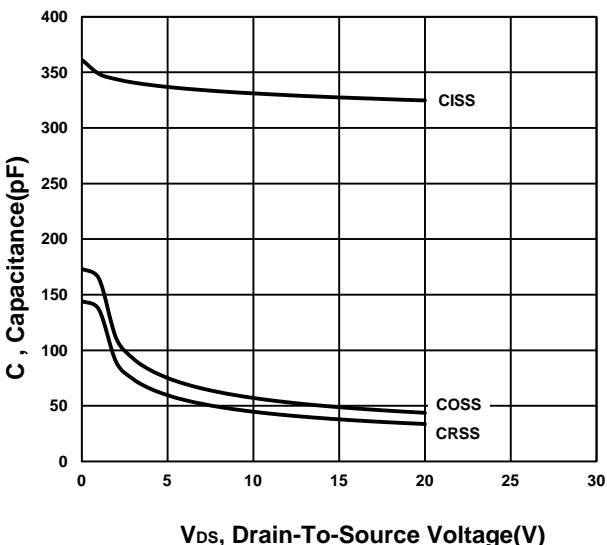
Transfer Characteristics



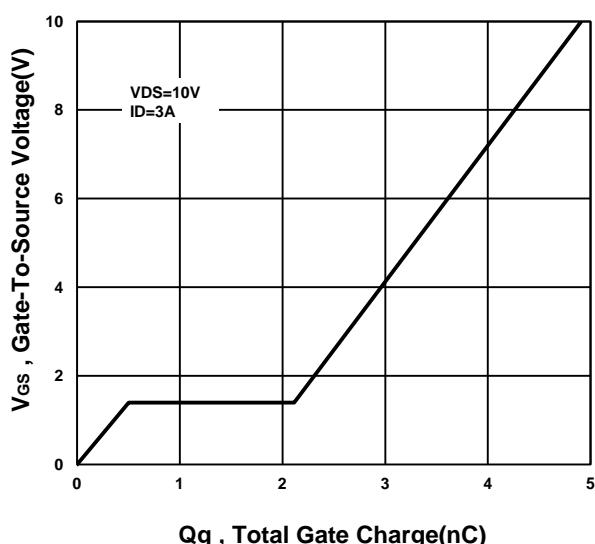
On-Resistance VS Temperature



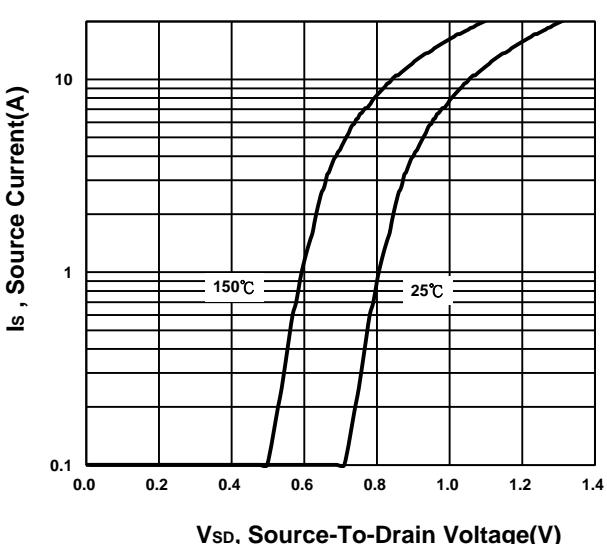
Capacitance Characteristic



Gate charge Characteristics



Source-Drain Diode Forward Voltage



NIKO-SEM

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